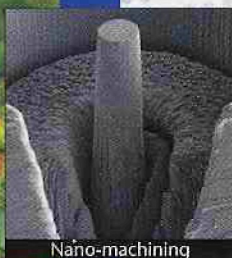
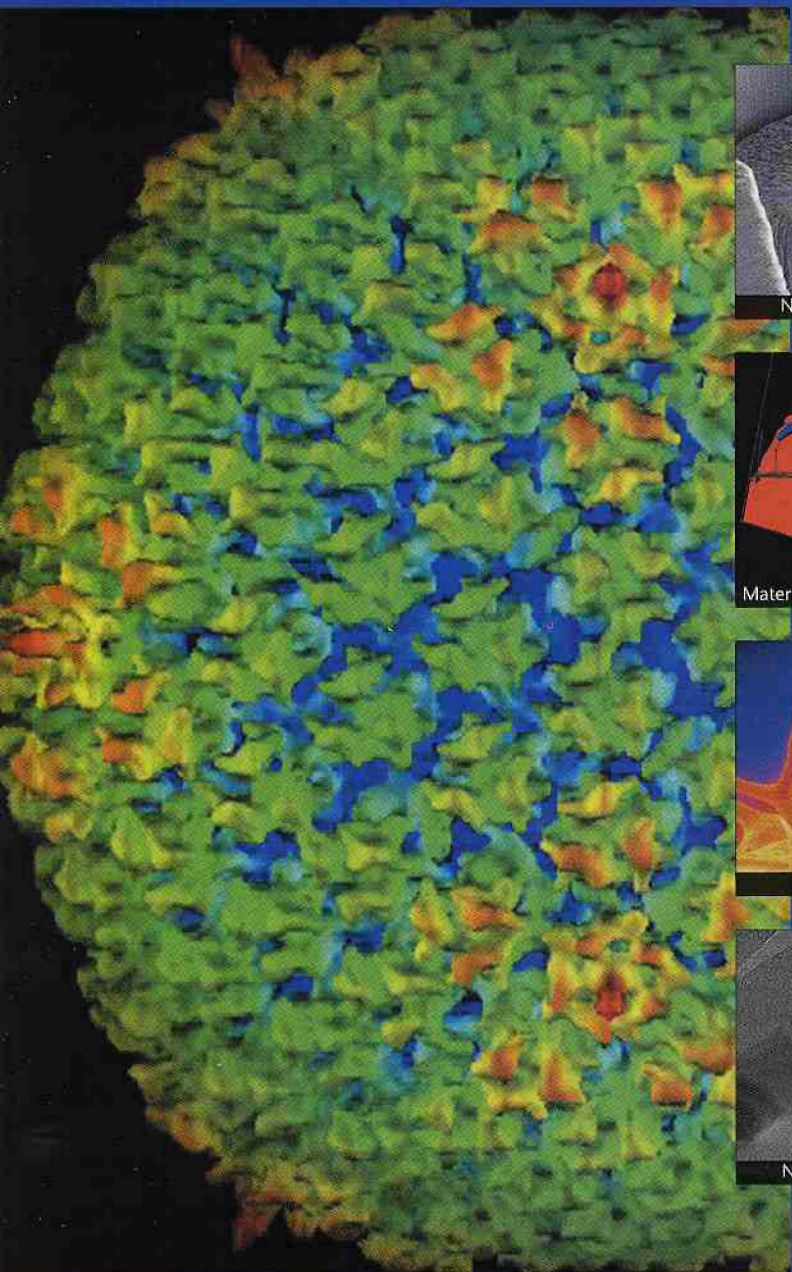


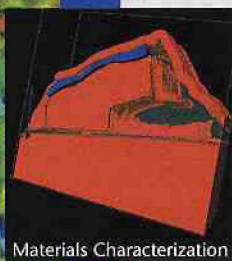
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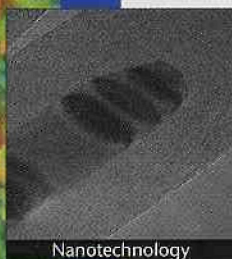
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We wish to thank Dr. Phoebe Stewart, Vanderbilt University Medical Center, for the three-dimensional reconstruction of adenovirus, a human respiratory virus, based on cryo-electron micrographs (large image). The viral surface is color coded according to height and the view is along a 2-fold icosahedral symmetry axis.

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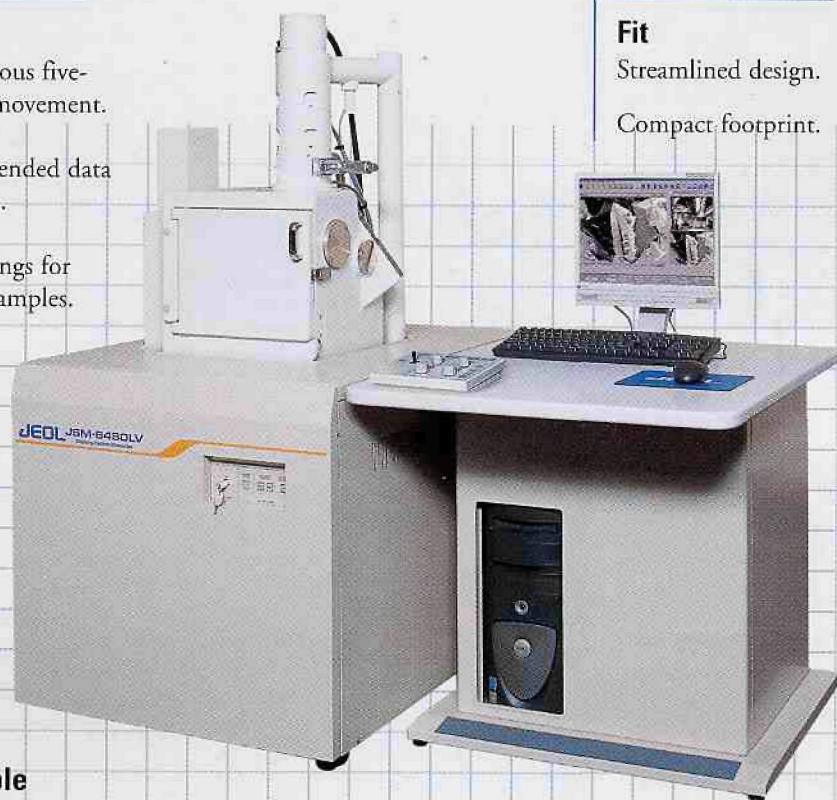
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